

**Search Notes**

Application/Control No.

10/047,177

Examiner

Erin M. File

Applicant(s)/Patent under  
Reexamination

LAI, YHEAN-SEN

Art Unit

2634

**SEARCHED**

Class	Subclass	Date	Examiner
375	348	11/18/2005	EMF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
PB PUB Text Search — See Printout History		11/18/2005	EMF

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	11/18/2005	EMF